



JPW

Docket No: 740819-1058

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of)
Hirosaki ISHIZUKA, et al.)
Application No. 10/827,414) Art Unit 2812
Filed: April 20, 2004)
For: METHOD FOR DETERMINING A)
PRECEDING WAFER, METHOD FOR)
DETERMINING A MEASURING WAFER,)
AND METHOD FOR ADJUSTING THE)
NUMBER OF WAFERS) Date: July 13, 2004

SUBSTITUTE INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

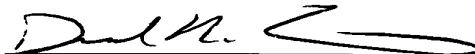
Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98

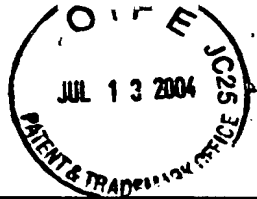
The references listed on the attached Form PTO-1449 were cited in parent application Serial No. 09/649,573 filed August 29, 2000, and its predecessors application Serial No. 10/431,513, from which priority is claimed under 35 U.S.C. 120.

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

By: 
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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known			
				Application Number		10/827,414	
				Filing Date		April 20, 2004	
				First Named Inventor		Hiroaki ISHIZUKA et al.	
				Art Unit		2812	
Examiner Name							
Sheet	1	of	1	Attorney Docket Number		740819-1058	

U.S. PATENT DOCUMENTS					
Examiner Initials ⁵	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
		US-5,989,762	11-23-1999	Takaoka	
		US-5,926,690	07-1999	Toprac et al.	
		US-6,485,990	11-26-2002	Jeremy Lansford	

FOREIGN PATENT DOCUMENTS						
Examiner Initials ⁵	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
		JP 07-099145	04-11-1995			Abstract

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials ⁵	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.